



P-Channel Enhancement Mode Field Effect Transistor

- **Features**

$V_{DS} (V) = -20V, I_D = -7A$

$R_{DS(ON)} < 30m\Omega @ V_{GS} = -4.5V$

$R_{DS(ON)} < 40m\Omega @ V_{GS} = -2.5V$

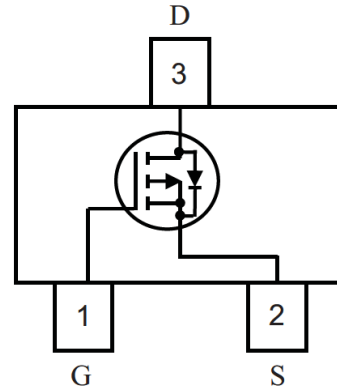
$R_{DS(ON)} < 55m\Omega @ V_{GS} = -1.8V$

SOT-23 Package

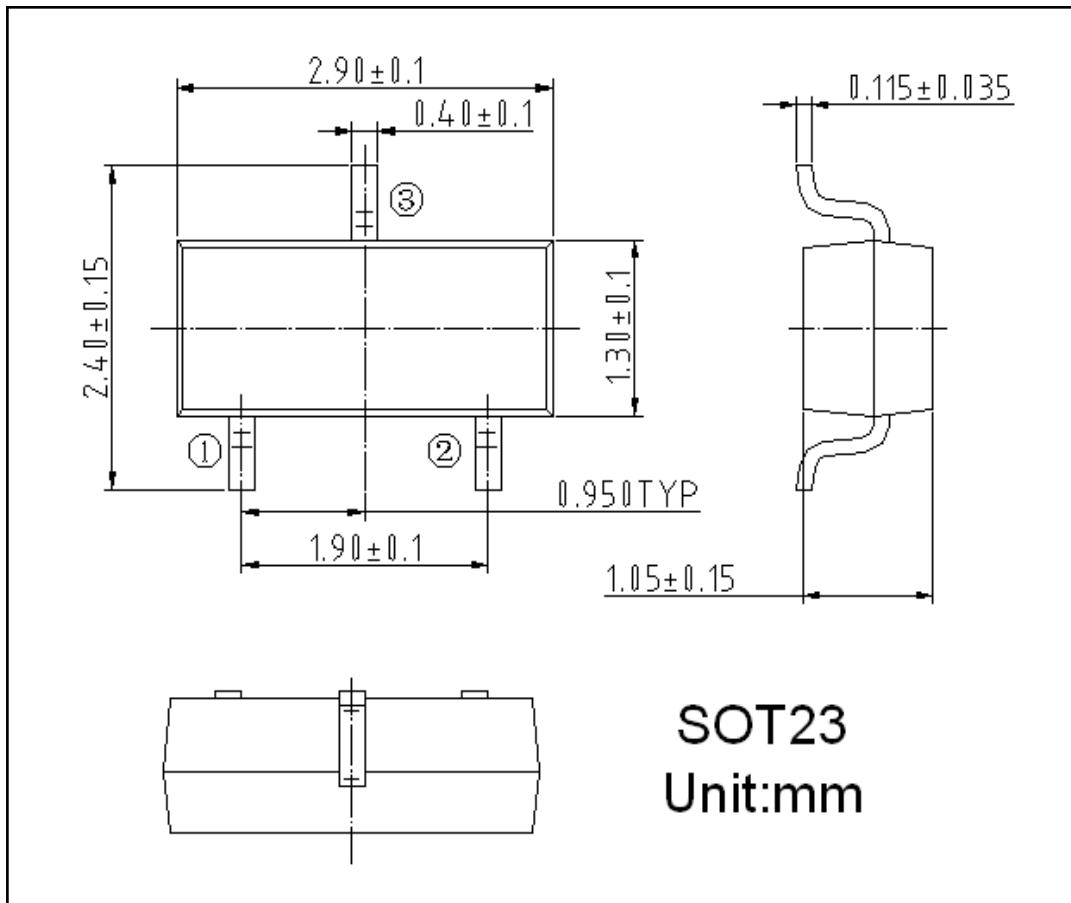
- **General Description**

The HX3413 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation gate voltages as low as 1.8V. This device is suitable for use as a load switch or other general applications.

- **Pin Configurations**



- **Package Information**





● **Absolute Maximum Ratings** @ $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DSS}	-20	V
Gate-Source Voltage		V_{GSS}	± 10	V
Drain Current (Continuous)	$T_A=25^\circ\text{C}$	I_D	-7.0	A
	$T_A=70^\circ\text{C}$		-5.8	
Drain Current (Pulse)		I_{DM}	-30	A
Power Dissipation	$T_A=25^\circ\text{C}$	P_D	1	W
Operating Temperature/ Storage Temperature		T_{J}/T_{STG}	-55~150	$^\circ\text{C}$

● **Electrical Characteristics** @ $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
ON/OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-20	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -20V, V_{GS} = 0V$	--	--	-1	μA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_{DS} = -250\mu\text{A}$	-0.6	-0.8	-1.4	V
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 10V, V_{DS} = 0V$	--	--	± 100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = -4.5V, I_D = -7A$	--	23	30	m Ω
		$V_{GS} = -2.5V, I_D = -2A$	--	29	40	m Ω
		$V_{GS} = -1.8V, I_D = -1.5A$	--	38	55	m Ω
Forward Transconductance	g_{fs}	$V_{DS} = -5V, I_D = -4A$	--	10	--	S
Diode Forward Voltage	V_{SD}	$I_{SD} = -1A, V_{GS} = 0V$	--	-0.78	-1.0	V
Switching CHARACTERISTICS						
Total Gate Charge	Q_g	$V_{GS} = -4.5V, V_{DS} = -10V, I_D = -4A$	--	9.5	--	nC
Gate-Source Charge	Q_{gs}		--	1.2	--	nC
Gate-Drain Charge	Q_{gd}		--	2.2	--	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{DS} = -10V, R_L = 2.5\Omega$ $I_D = -3A, V_{GS} = -4.5V$ $R_G = 3\Omega$	--	18	--	ns
Turn-on Rise Time	t_r		--	11	--	ns
Turn-off Delay Time	$t_{d(off)}$		--	36.7	--	ns
Turn-off Fall Time	t_f		--	48	--	ns
Dynamic CHARACTERISTICS						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -10V, f = 1.0\text{MHz}$	--	826	--	pF
Output Capacitance	C_{oss}		--	90.7	--	pF
Reverse Transfer Capacitance	C_{rss}		--	53.2	--	pF

Pulse Test: Pulse Width $\leq \mu 300s$, Duty Cycle $\leq 2.0\%$



Typical Performance Characteristics

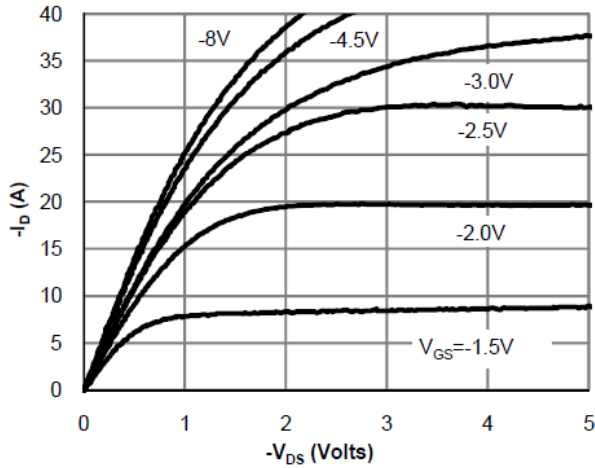


Fig 1: On-Region Characteristics

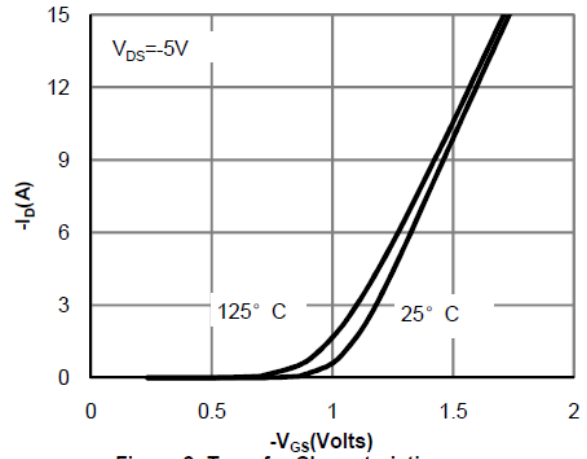


Figure 2: Transfer Characteristics

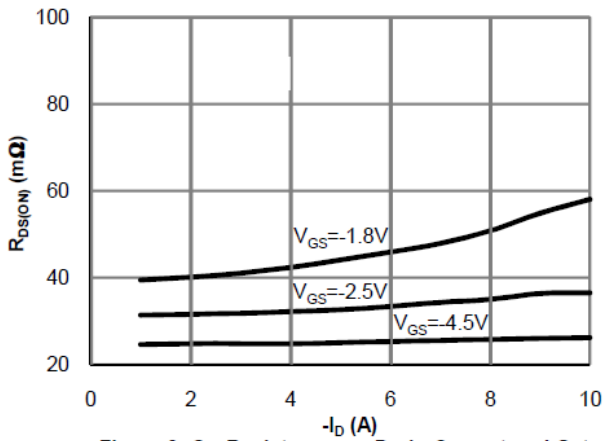


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

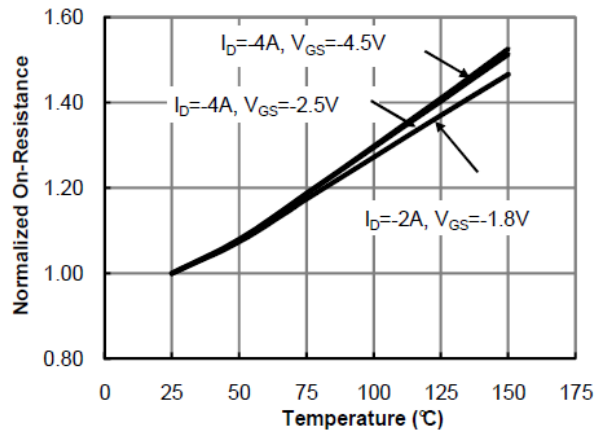


Figure 4: On-Resistance vs. Junction Temperature

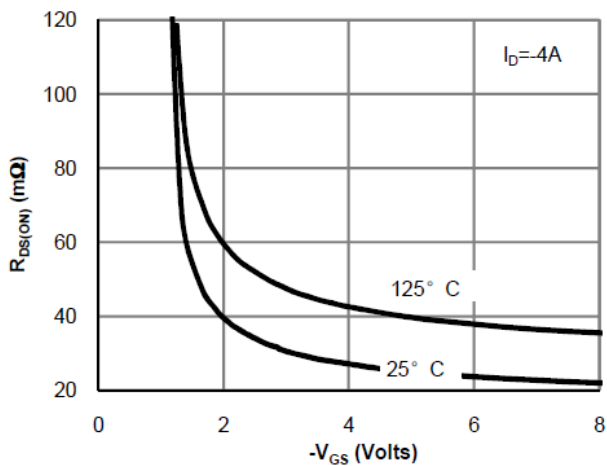


Figure 5: On-Resistance vs. Gate-Source Voltage

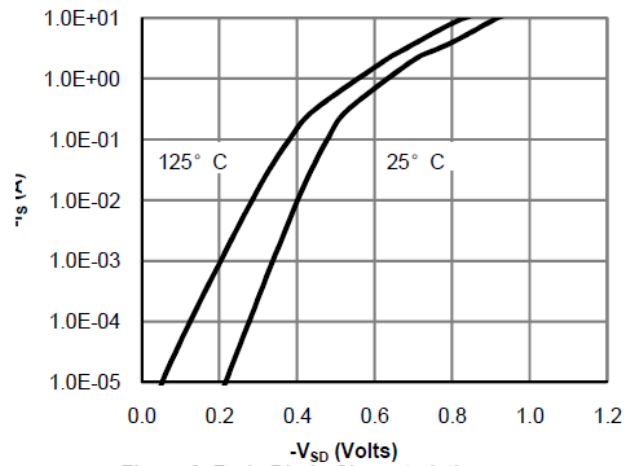


Figure 6: Body-Diode Characteristics



Typical Performance Characteristics

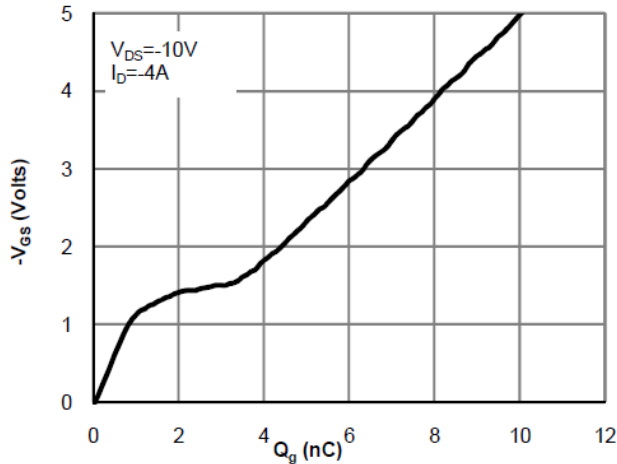


Figure 7: Gate-Charge Characteristics

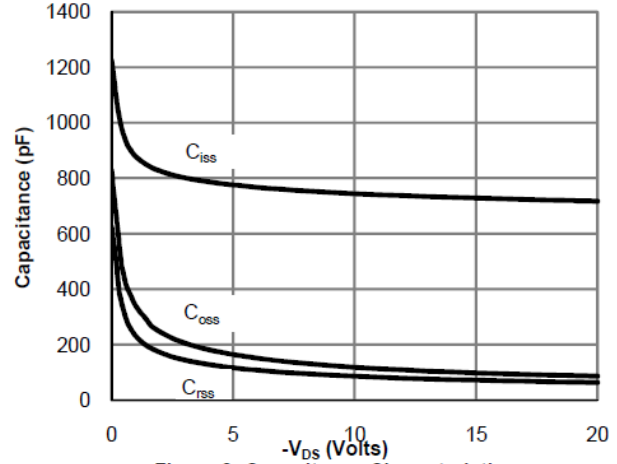


Figure 8: Capacitance Characteristics

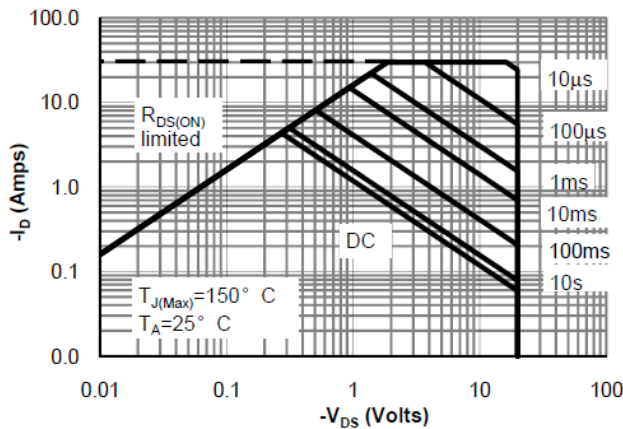


Figure 9: Maximum Forward Biased Safe Operating Area

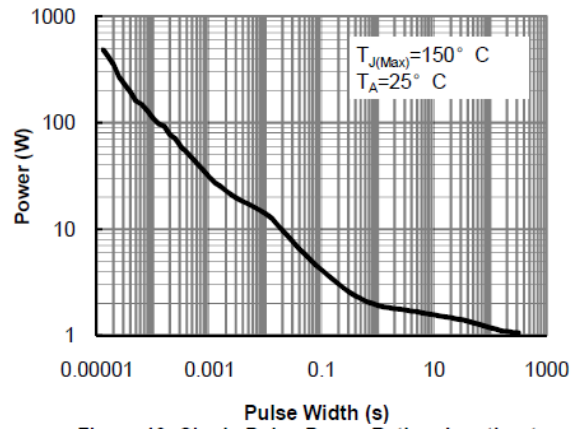


Figure 10: Single Pulse Power Rating Junction-to-Ambient

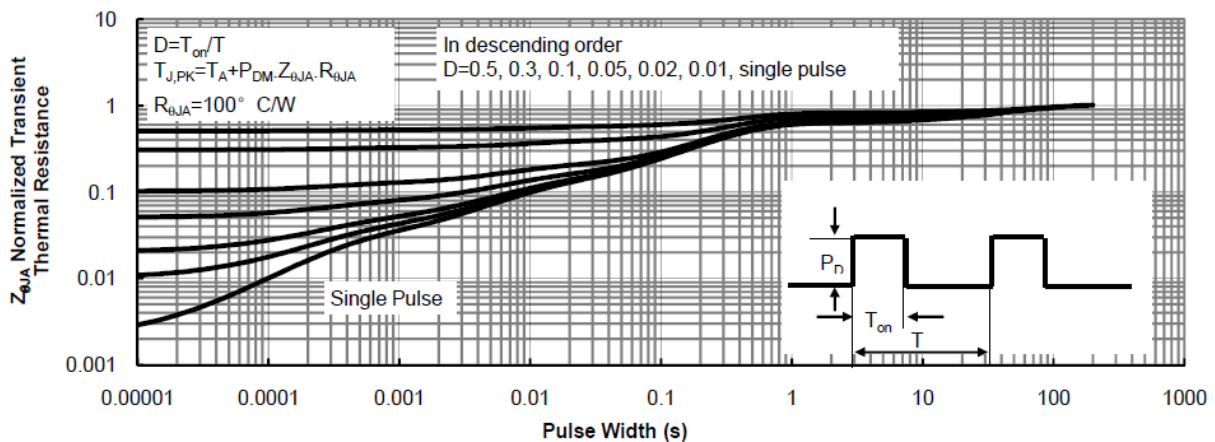


Figure 11: Normalized Maximum Transient Thermal Impedance



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